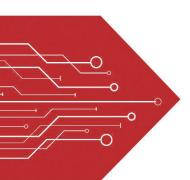
# MSKSEMI















**ESD** 

TVS

TSS

MOV

**GDT** 

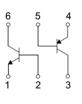
**PLED** 

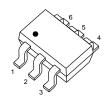
# Brodnet data speet

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**SOT-363** 

MAKING: K46 •

## **MMDT3946**

**DUAL TRANSISTOR (NPN+PNP)** 

#### **FEATURES**

- Complementary Pair
- One 3904-Type NPN
  One 3906-Type PNP
- Epitaxial Planar Die Construction
- Ideal for Low Power Amplification and Switching

#### MAXIMUM RATINGS (T<sub>a</sub>=25℃ unless otherwise noted)

Symbol	Parameter	Value	Units
V <sub>CBO</sub>	Collector-Base Voltage	60	V
V <sub>CEO</sub>	Collector-Emitter Voltage	40	V
V <sub>EBO</sub>	Emitter-Base Voltage	5	V
Ic	Collector Current -Continuous	0.2	Α
Pc	Collector Power Dissipation	0.2	W
TJ	Junction Temperature	150	$^{\circ}\!\mathbb{C}$
T <sub>stg</sub>	Storage Temperature	-55-150	$^{\circ}\!\mathbb{C}$

### NPN 3904 ELECTRICAL CHARACTERISTICS (Ta=25℃ unless otherwise specified)

Parameter	Symbol	Test conditions	Min	Max	Unit
Collector-base breakdown voltage	V <sub>(BR)CBO</sub>	$I_{CBO}$ $I_{C} = 10\mu A$ , $I_{E} = 0$			V
Collector-emitter breakdown voltage	V <sub>(BR)CEO</sub>	I <sub>C</sub> = 1mA, I <sub>B</sub> =0	40		V
Emitter-base breakdown voltage	V <sub>(BR)EBO</sub>	I <sub>E</sub> = 10μA, I <sub>C</sub> =0	5		V
Collector cut-off current	I <sub>CBO</sub>	V <sub>CB</sub> = 30 V , I <sub>E</sub> =0		0.05	μA
Collector cut-off current	I <sub>CEO</sub>	V <sub>CE</sub> = 30 V , I <sub>B</sub> =0		0.5	μA
Emitter cut-off current	I <sub>EBO</sub>	V <sub>EB</sub> = 5V , I <sub>C</sub> =0		0.05	μA
	h <sub>FE(1)</sub>	$V_{CE}$ = 1V, $I_{C}$ = 0.1mA	40		
	h <sub>FE(2)</sub>	V <sub>CE</sub> = 1V, I <sub>C</sub> = 1mA	70		
DC current gain	h <sub>FE(3)</sub>	V <sub>CE</sub> = 1V, I <sub>C</sub> = 10mA	100	300	
	h <sub>FE(4)</sub>	V <sub>CE</sub> = 1V, I <sub>C</sub> = 50mA	60		
	h <sub>FE(5)</sub>	V <sub>CE</sub> = 1V, I <sub>C</sub> = 100mA	30		
Collector-emitter saturation voltage	V <sub>CE(sat)1</sub>	I <sub>C</sub> =10 mA, I <sub>B</sub> = 1mA		0.2	V
Conector-entitler saturation voltage	V <sub>CE(sat)2</sub>	$I_C$ =50 mA, $I_B$ = 5mA		0.3	V
Base-emitter saturation voltage	V <sub>BE(sat)1</sub>	I <sub>C</sub> = 10 mA, I <sub>B</sub> = 1mA	0.65	0.85	V
Dase-enlitter saturation voltage	V <sub>BE(sat)2</sub>	I <sub>C</sub> = 50 mA, I <sub>B</sub> = 5mA		0.95	V
Transition frequency	f⊤	V <sub>CE</sub> =20V,I <sub>C</sub> =20mA, f=100MHz	300		MHz
Noise figure	NF	$V_{CE}$ =5V, $I_c$ =0.1mA, f=1KHz,Rg=1K $\Omega$		5	dB
Output capacitance	C <sub>ob</sub>	V <sub>CB</sub> =5V,I <sub>E</sub> =0,f=1MHz		4	pF
Delay time	t <sub>d</sub>	V <sub>CC</sub> =3V, V <sub>BE</sub> =0.5V		35	nS
Rise time	t <sub>r</sub>	I <sub>C</sub> =10mA , I <sub>B1</sub> =- I <sub>B2</sub> =1mA		35	nS
Storage time	ts	V <sub>CC</sub> =3V, I <sub>C</sub> =10mA		200	nS
Fall time	t <sub>f</sub>	I <sub>B1</sub> =-I <sub>B2</sub> = 1mA		50	nS

## MAXIMUM RATINGS(T<sub>a</sub>=25°C unless otherwise noted)

Symbol	Parameter	Value	Units	
V <sub>CBO</sub>	Collector-Base Voltage	-40	V	
V <sub>CEO</sub>	Collector-Emitter Voltage	-40	V	
V <sub>EBO</sub>	Emitter-Base Voltage	-5	V	
Ic	Collector Current -Continuous	-0.2	Α	
Pc	Collector Power Dissipation	0.2	W	
TJ	Junction Temperature	150	°C	
T <sub>stg</sub>	Storage Temperature	-55-150	°C	

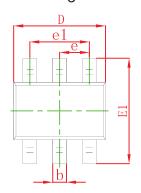
# PNP 3906 ELECTRICAL CHARACTERISTICS (Ta=25°C unless otherwise specified)

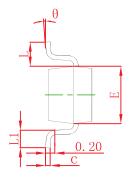
Parameter	Symbol	Test conditions	Min	Тур	Max	Unit
Collector-base breakdown voltage	V <sub>(BR)CBO</sub>	I <sub>C</sub> =-10μA,I <sub>E</sub> =0	-40			V
Collector-emitter breakdown voltage	V <sub>(BR)CEO</sub>	I <sub>C</sub> =-1mA,I <sub>B</sub> =0	-40			V
Emitter-base breakdown voltage	V <sub>(BR)EBO</sub>	I <sub>E</sub> =-10μA,I <sub>C</sub> =0	-5			V
Collector cut-off current	I <sub>CBO</sub>	V <sub>CB</sub> =-30V,I <sub>E</sub> =0			-0.05	μΑ
Emitter cut-off current	I <sub>EBO</sub>	V <sub>EB</sub> =-5V,I <sub>C</sub> =0			-0.05	μΑ
	h <sub>FE(1)</sub>	V <sub>CE</sub> =-1V,I <sub>C</sub> =-0.1mA	60			
	h <sub>FE(2)</sub>	V <sub>CE</sub> =-1V,I <sub>C</sub> =-1mA	80			
DC current gain	h <sub>FE(3)</sub>	V <sub>CE</sub> =-1V,I <sub>C</sub> =-10mA	100		300	
	h <sub>FE(4)</sub>	V <sub>CE</sub> =-1V,I <sub>C</sub> =-50mA	60			
	h <sub>FE(5)</sub>	V <sub>CE</sub> =-1V,I <sub>C</sub> =-100mA	30			
Collector-emitter saturation voltage	V <sub>CE(sat)1</sub>	I <sub>C</sub> =-10mA,I <sub>B</sub> =-1mA			-0.25	V
Conector-entitler saturation voltage	V <sub>CE(sat)2</sub>	I <sub>C</sub> =-50mA,I <sub>B</sub> =-5mA			-0.4	V
Page emitter acturation voltage	V <sub>BE(sat)1</sub>	I <sub>C</sub> =-10mA,I <sub>B</sub> =-1mA	-0.65		-0.85	V
Base-emitter saturation voltage	V <sub>BE(sat)2</sub>	I <sub>C</sub> =-50mA,I <sub>B</sub> =-5mA			-0.95	V
Transition frequency	f <sub>T</sub>	V <sub>CE</sub> =-20V,I <sub>C</sub> =-10mA,f=100MHz	250			MHz
Collector output capacitance	C <sub>ob</sub>	V <sub>CB</sub> =-5V,I <sub>E</sub> =0,f=1MHz			4.5	pF
Noise figure	NF	$V_{CE}$ =-5V,I <sub>c</sub> =-0.1mA, f=1KHz,Rg=1K $\Omega$			4	dB
Delay time	t <sub>d</sub>	V <sub>CC</sub> =-3V, V <sub>BE</sub> =-0.5V			35	nS
Rise time	t <sub>r</sub>	I <sub>C</sub> =-10mA , I <sub>B1</sub> =-I <sub>B2</sub> =-1mA			35	nS
Storage time	ts	V <sub>CC</sub> =-3V, I <sub>C</sub> =-10mA			225	nS
Fall time	t <sub>f</sub>	I <sub>B1</sub> =-I <sub>B2</sub> =- 1mA			75	nS

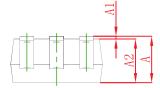




# SOT-363 Package Outline Dimensions

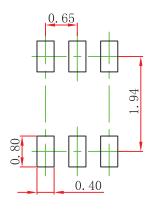






Symbol	Dimensions In Millimeters		Dimension	s In Inches
Symbol	Min	Max	Min	Max
Α	0.900	1.100	0.035	0.043
A1	0.000	0.100	0.000	0.004
A2	0.900	1.000	0.035	0.039
b	0.150	0.350	0.006	0.014
С	0.100	0.150	0.004	0.006
D	2.000	2.200	0.079	0.087
E	1.150	1.350	0.045	0.053
E1	2.150	2.400	0.085	0.094
е	0.650 TYP		0.026	S TYP
e1	1.200	1.400	0.047	0.055
L	0.525 REF		0.021	REF
L1	0.260	0.460	0.010	0.018
θ	0°	8°	0°	8°

## SOT-363 Suggested Pad Layout



#### Note:

- 1.Controlling dimension:in millimeters.
- 2.General tolerance:± 0.05mm.
- 3. The pad layout is for reference purposes only.

## **REEL SPECIFICATION**

P/N	PKG	QTY
MMDT3946	SOT-363	3000



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